

# SN74AS1008A QUADRUPLE 2-INPUT POSITIVE-AND BUFFER/DRIVER

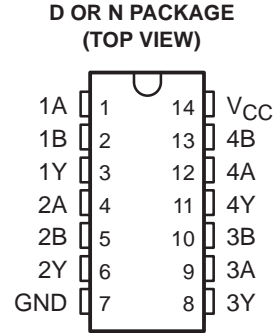
SDAS071B – DECEMBER 1982 – REVISED JANUARY 1995

- Driver Version of 'AS08
- Offers High Capacitive-Drive Capability
- Package Options Include Plastic Small-Outline (D) Packages and Standard Plastic (N) 300-mil DIPs

## description

This device contains four independent 2-input positive-AND buffers/drivers. It performs the Boolean functions  $Y = A \bullet B$  or  $Y = \overline{A + B}$  in positive logic.

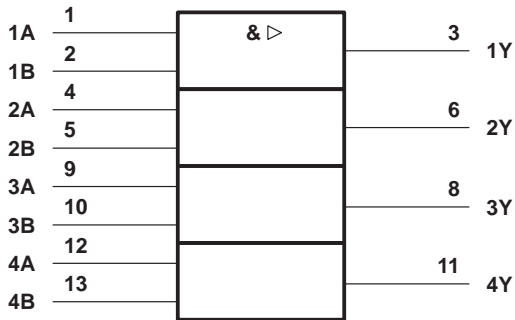
The SN74AS1008A is characterized for operation from 0°C to 70°C.



**FUNCTION TABLE  
(each gate)**

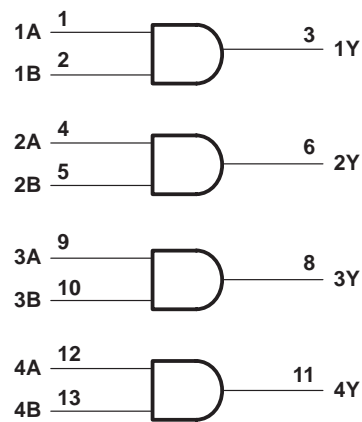
INPUTS		OUTPUT
A	B	Y
H	H	H
L	X	L
X	L	L

## logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

## logic diagram (positive logic)



## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage, V <sub>CC</sub>	7 V
Input voltage, V <sub>I</sub>	7 V
Operating free-air temperature range, T <sub>A</sub>	0°C to 70°C
Storage temperature range	–65°C to 150°C

‡ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

# SN74AS1008A

## QUADRUPLE 2-INPUT POSITIVE-AND BUFFER/DRIVER

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### recommended operating conditions†

		MIN	NOM	MAX	UNIT
$V_{CC}$	Supply voltage	4.5	5	5.5	V
$V_{IH}$	High-level input voltage	2			V
$V_{IL}$	Low-level input voltage			0.8	V
$I_{OH}$	High-level output current			-48	mA
$I_{OL}$	Low-level output current			48	mA
$T_A$	Operating free-air temperature	0		70	°C

† This high sink- or source-current device is not recommended for use above 40 MHz.

### electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP‡	MAX	UNIT
$V_{IK}$	$V_{CC} = 4.5\text{ V}$ , $I_I = -18\text{ mA}$			-1.2	V
$V_{OH}$	$V_{CC} = 4.5\text{ V to } 5.5\text{ V}$ , $I_{OH} = -2\text{ mA}$	$V_{CC} - 2$			V
	$V_{CC} = 4.5\text{ V}$ , $I_{OH} = -3\text{ mA}$	2.4	3.2		
	$V_{CC} = 4.5\text{ V}$ , $I_{OH} = -48\text{ mA}$	2			
$V_{OL}$	$V_{CC} = 4.5\text{ V}$ , $I_{OL} = 48\text{ mA}$		0.35	0.5	V
$I_I$	$V_{CC} = 5.5\text{ V}$ , $V_I = 7\text{ V}$			0.1	mA
$I_{IH}$	$V_{CC} = 5.5\text{ V}$ , $V_I = 2.7\text{ V}$			20	μA
$I_{IL}$	$V_{CC} = 5.5\text{ V}$ , $V_I = 0.4\text{ V}$			-0.5	mA
$I_{O}^{\S}$	$V_{CC} = 5.5\text{ V}$ , $V_O = 2.25\text{ V}$	-50		-200	mA
$I_{CCH}$	$V_{CC} = 5.5\text{ V}$ , $V_I = 4.5\text{ V}$		5.6	9.5	mA
$I_{CCL}$	$V_{CC} = 5.5\text{ V}$ , $V_I = 0$		13.5	22	mA

‡ All typical values are at  $V_{CC} = 5\text{ V}$ ,  $T_A = 25^\circ\text{C}$ .

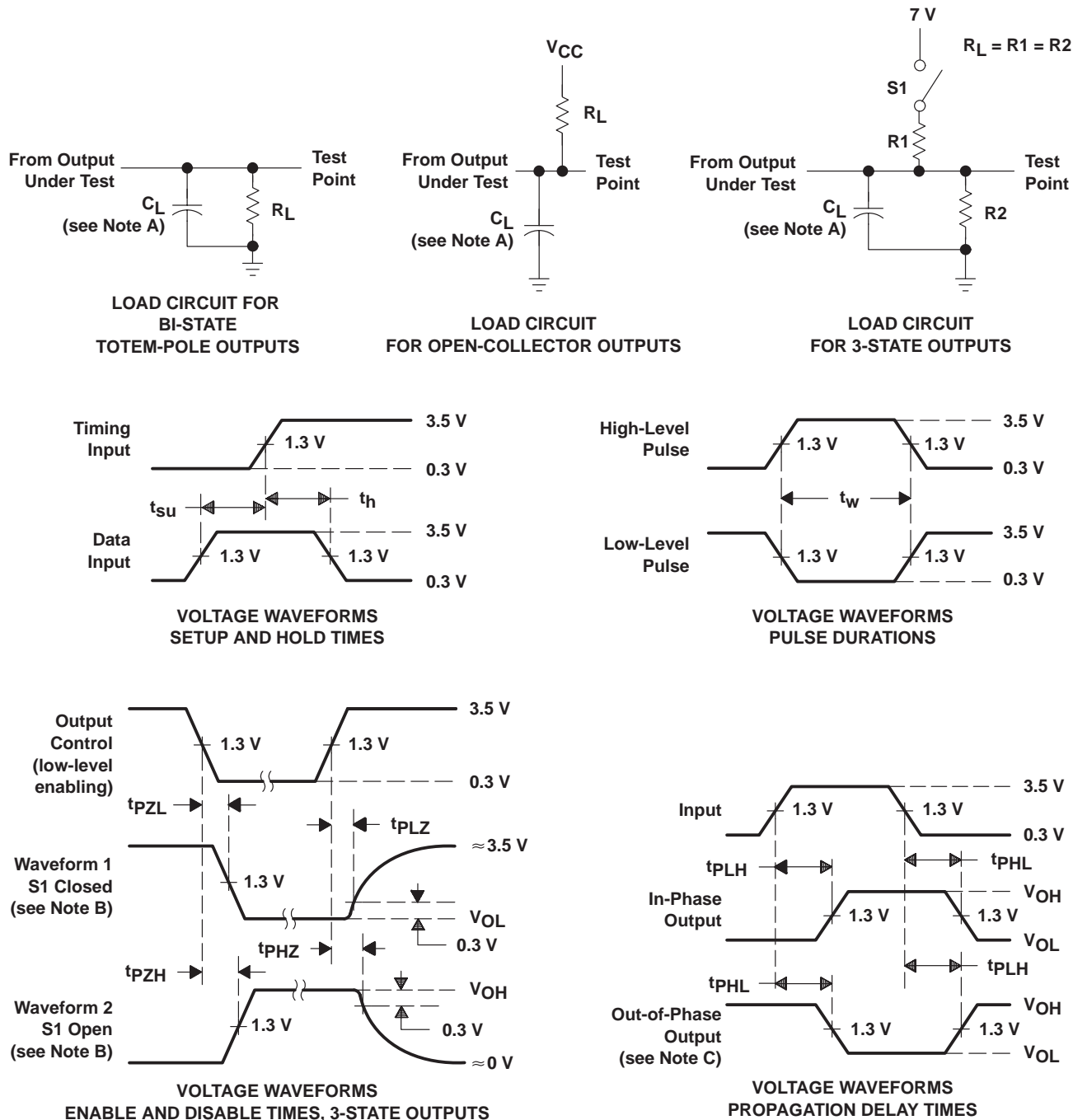
§ The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current,  $I_{OS}$ .

### switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 4.5\text{ V to } 5.5\text{ V}$ , $C_L = 50\text{ pF}$ , $R_L = 500\ \Omega$ , $T_A = \text{MIN to MAX}^{\parallel}$		UNIT
			MIN	MAX	
$t_{PLH}$	A or B	Y	1	6	ns
$t_{PHL}$			1	6	

<sup>¶</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

PARAMETER MEASUREMENT INFORMATION  
 SERIES 54ALS/74ALS AND 54AS/74AS DEVICES



- NOTES: A.  $C_L$  includes probe and jig capacitance.  
 B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.  
 C. When measuring propagation delay items of 3-state outputs, switch S1 is open.  
 D. All input pulses have the following characteristics:  $PRR \leq 1$  MHz,  $t_r = t_f = 2$  ns, duty cycle = 50%.  
 E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms

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